Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2232

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

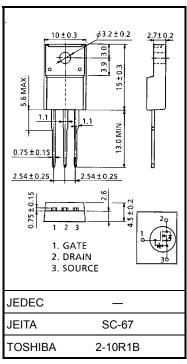
Low drain-source ON resistance : RDS (ON) = 36 mΩ (typ.)
 High forward transfer admittance : | Yfs | = 16 S (typ.)

• Low leakage current : $IDSS = 100 \mu A (max) (VDS = 60 V)$

• Enhancement mode : $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V}, I_D = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	60	V
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	60	V
Gate-source voltage		V_{GSS}	±20	V
Drain current	DC (Note 1)	I_{D}	25	Α
	Pulse (Note 1)	I_{DP}	100	Α
Drain power dissipation	n (Tc = 25°C)	P_{D}	35	W
Single pulse avalanch	e energy (Note 2)	E _{AS}	156	mJ
Avalanche current		I _{AR}	25	Α
Repetitive avalanche	energy (Note 3)	E _{AR}	3.5	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C



Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	3.57	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 339 μ H, R_{G} = 25 Ω , I_{AR} = 25 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature.

This transistor is an electrostatic-sensitive device.

Please handle with caution.



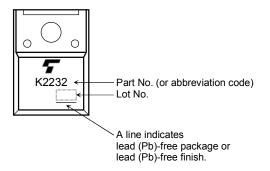
Electrical Characteristics (Ta = 25°C)

Charao	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br voltage	reakdown	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	٧
Gate threshold	voltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	8.0	_	2.0	V
Drain-source ON resistance		Pag (au)	V _{GS} = 4 V, I _D = 12 A	_	0.057	0.08	Ω
		R _{DS} (ON)	V _{GS} = 10 V, I _D = 12 A	_	0.036	0.046	12
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 12 A	10	16	_	S
Input capacitano	ce	C _{iss}		_	1000	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	200	_	pF
Output capacitance		Coss		_	550	_	
Switching time	Rise time	t _r	$V_{GS} = 10V$ $V_{GS} = 10V$ $V_{DD} = 30V$ $V_{DD} = 30V$	_	20	_	
	Turn-on time	t _{on}		_	30	_	nc
	Fall time	t _f		_	55	_	ns ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\mathbf{W}} = 10 \mu \text{s}$	_	130	_	
Total gate charge (Gate-source plus gate-drain)		Qg			38	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 48 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 25 \text{ A}$		25	_	nC
Gate-drain ("miller") charge		Q _{gd}			13		

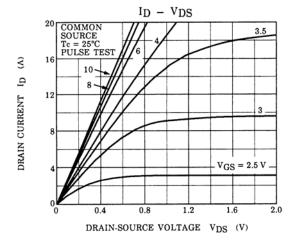
Source-Drain Ratings and Characteristics (Ta = 25°C)

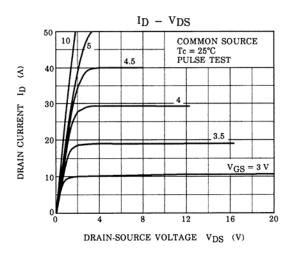
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	25	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	100	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 25 A, V _{GS} = 0 V	_	_	-1.8	V
Reverse recovery time	t _{rr}	I _{DR} = 25 A, V _{GS} = 0 V, dI _{DR} / dt = 50 A / μs	_	50	_	ns
Reverse recovered charge	Qrr	1DR - 25 A, VGS - 0 V, αIDR / αt - 50 A / μs		35	_	μC

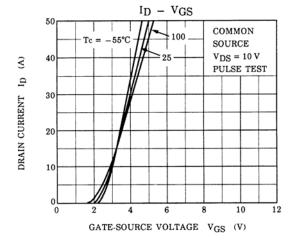
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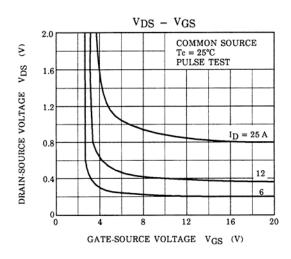


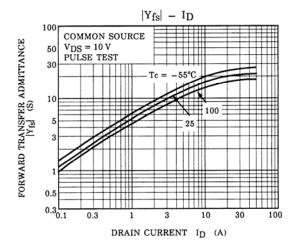
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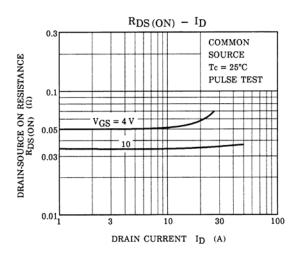


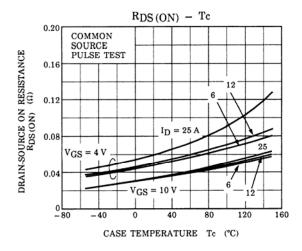


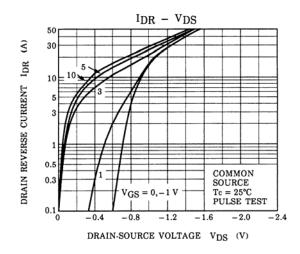


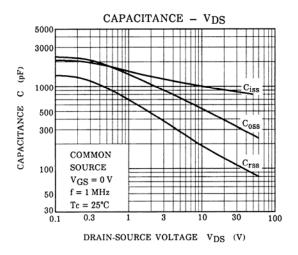


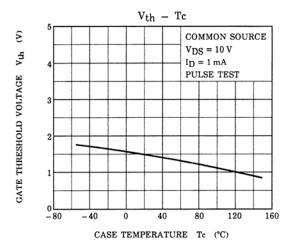


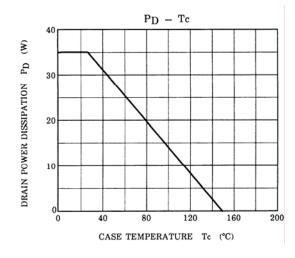


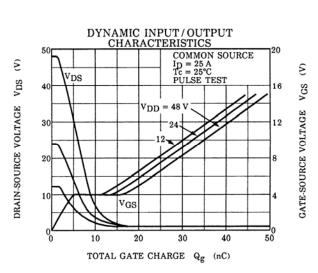




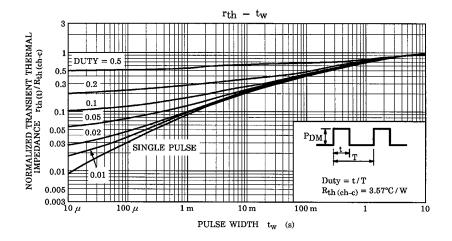


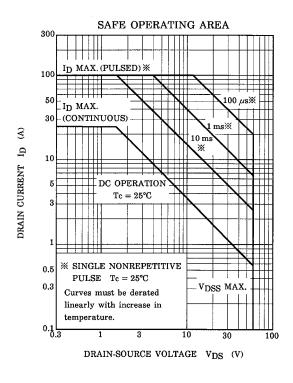


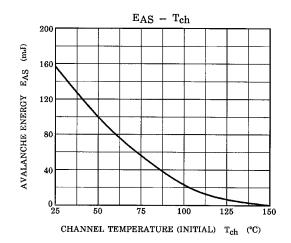


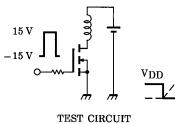


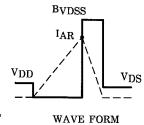
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$$R_G$$
 = 25 Ω
 V_{DD} = 25 V, L = 339 μ H

$$EAS = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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